

10/512082

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SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 261333US2PCT		SERIAL NO. New U.S. PCT Application Based on PCT/JP02/06127	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Takao SAWADA, et al.			
				FILING DATE Herewith		GROUP 2879	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
PM	AO	2000-40461	02/08/00	JP		NO	
	AP	58-189940	11/05/83	JP		NO	
	AQ	61-4133	01/10/86	JP		NO	
	AR	9-190761	07/22/97	JP (equivalent of US 6091189)		NO	
	AS	2000-251613	09/14/00	JP		NO	
	AT	9-106750	04/22/97	JP (equivalent of US 5118984)		NO	
	AU	2758244	03/13/98	JP (equivalent of US 5118984)		NO	
PM	AV	54-83360	07/03/79	JP (equivalent of US 4273683)		NO	
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
PM	AW	HAYASHIDA, Y. et al. "An Analysis of Cut-Off Voltage Drift in the Oxide Cathode Life", Electronics Research Laboratory, Matsushita Electronics Corporation, pages 67-72, with English abstract 1995					
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner /Peter Macchiarolo/ (09/16/2006)					Date Considered 09/16/2006		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							